


<b>Search Notes</b> 	<b>Application/Control No.</b> 10824445	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> Tan, Alvin H	<b>Art Unit</b> 2173

SEARCHED			
Class	Subclass	Date	Examiner
715	708	5/22/07	AT
345	581	5/22/07	AT
Above	UPDATED	11/5/07	AT

SEARCH NOTES		
Search Notes	Date	Examiner
715/705, 708, 712, 764, 810 (text search only - see search history printout)	5/23/07	AT
345/581, 589, 617, 902 (text search only - see search history printout)	5/22/07	AT
348/177, 178 (text search only - see search history printout)	5/29/07	AT
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	5/25/07	AT
Above - UPDATED	11/5/07	AT
NPL (ACM Portal, Google.com)	5/25/07	AT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner